

LANGER



IC-Scanner

ICS 103

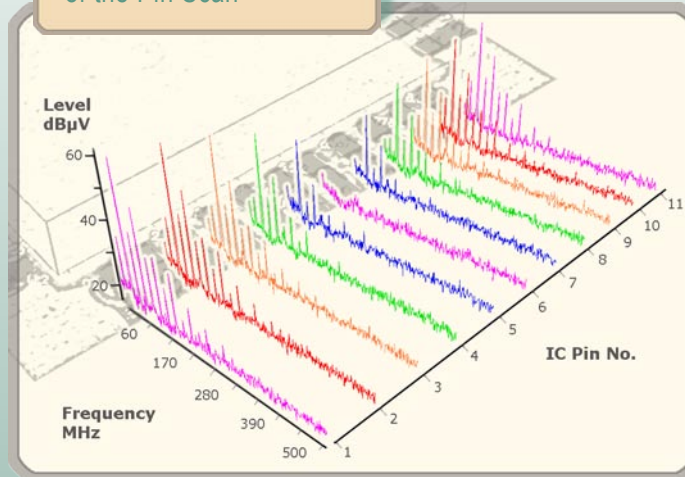
*Measurement of
radiated fields
over an IC or DIE
IEC 61967-3*



LANGER EMV-Technik GmbH

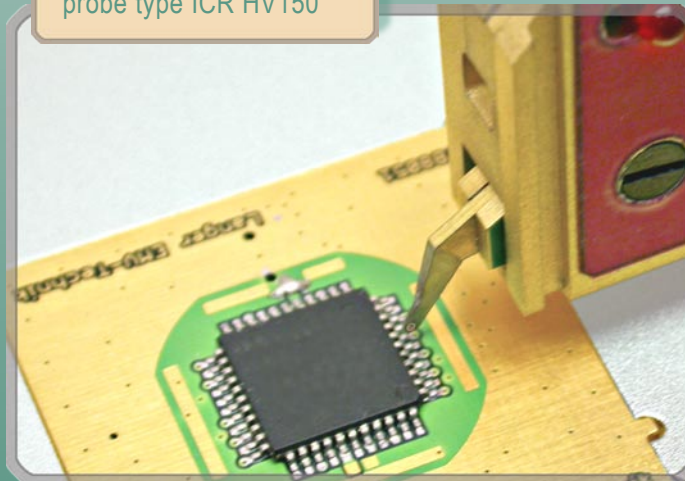
ChipScan

3D view of the
measured spectra
of the Pin Scan



Pin Scan

ICR probe moves
from pin to pin with
probe type ICR HV150



System specification

Measuring range: ICS 103
x, y and z axes [mm]: 25 mm
rotation axis [rad]: +/- 180°

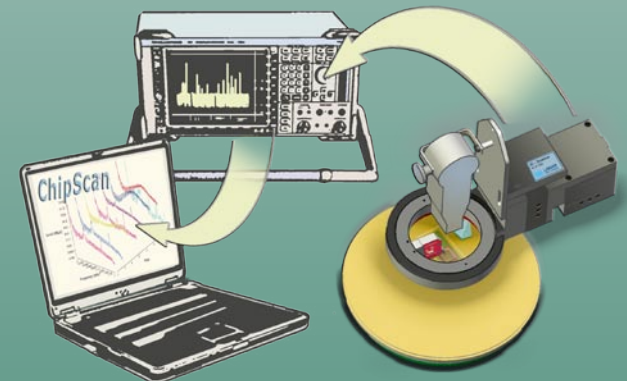
Alignment accuracy:
x, y and z axes: 0.01 mm
rotation axis: 1.0°

Near field microprobes:

- magnetic field ICR HH 100 - 500 horizontal polarisation
ICR HV 100 - 500 vertical polarisation
- measurement resolution - min 50 µm
- electric field ICR E 150 horizontal
- with preamplifier 30 dB / 50 Ohm
- frequency range 200 kHz up to 6 GHz

System architecture

Measuring probes: Active near field microprobes
Measuring unit: Spectrum analyzer
Control unit: IBM compatible PC with
Microsoft Windows®
Software: ChipScan



www.langer-emv.com